ELECTRONIC SUPPLEMENTARY INFORMATION

Structural characterization of electrodeposited copper hexacyanoferrate films by using a spectroscopic multi-technique approach†

Marco Giorgetti*[1], Lorella Guadagnini[1], Domenica Tonelli[1], Marco Minicucci[2], Giuliana Aquilanti[3]

1. Department of Physical and Inorganic Chemistry, University of Bologna, and INSTM, Viale Risorgimento, 4 40136 Bologna, Italy, INSTM, UdR Bologna

2. CNISM, School of Science and Technology, Physics Division, Università di Camerino, via Madonna delle Carceri, 62032 Camerino (MC), Italy;

3. Sincrotrone Trieste S.C.p.A., S.S. 14 Km 163.5, 34149 Basovizza, Trieste, Italy;

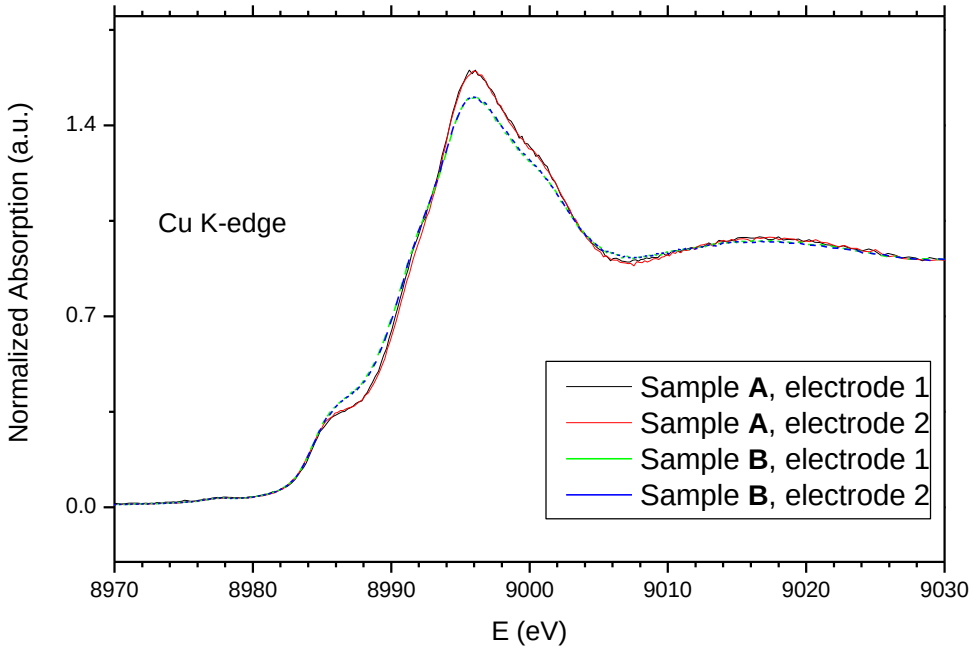

Figure S1. XANES spectra of several investigated electrodes taken at the Cu K-edge. The curves corresponding to the same compound (either sample A or B) are superimposable, demonstrating the reproducibility of the electrodes in different batches.

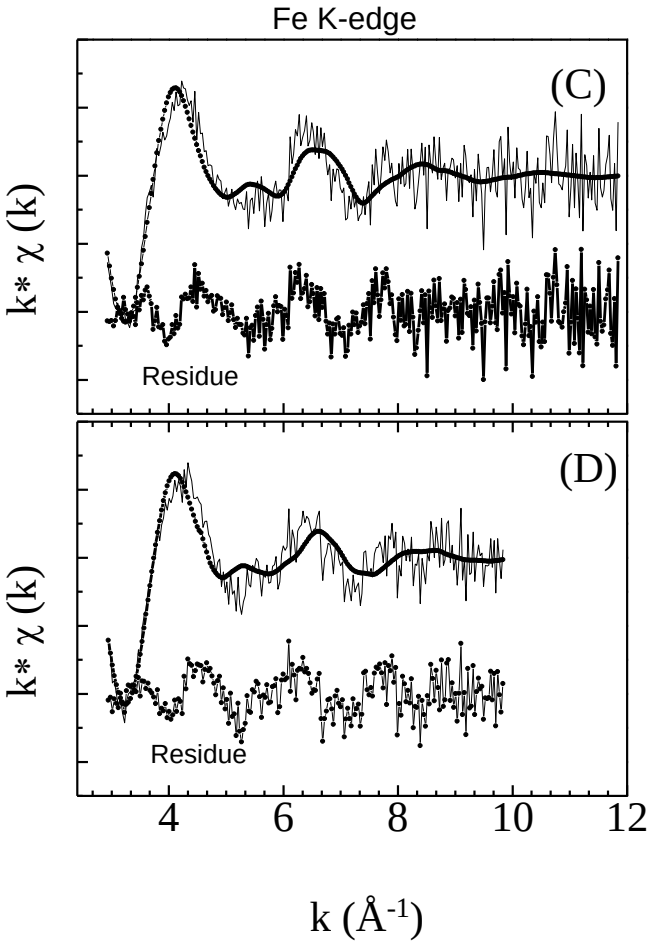

Figure S2. Preliminary EXAFS fitting at the Fe K-edge of electrodes **C** and **D** showing the comparison of the experimental (solid lines) and theoretical (dotted lines) k^2-extracted EXAFS signals. The residual curve is also displayed at the bottom of each panel.

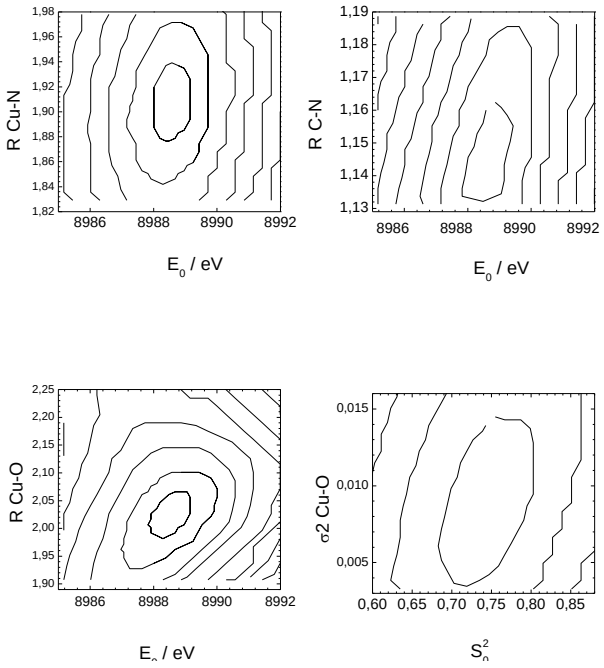

Figure S3. Examples of the two-dimensional section of the parameter space (contour plots) for electrode **C**. These plots were selected among the parameters having strong correlation to reflect the highest error. This evaluation provides only statistical errors on EXAFS refined parameters. The inner elliptical contour corresponds to the 95% confidence level.